

[54] DATA PROCESSOR FOR MEASURING INSTRUMENTS

[75] Inventors: Seigo Takahashi; Takeji Nishimura; Hiroshi Koizumi, all of Kawasaki, Japan

[73] Assignee: Mitutoyo Mfg. Co., Ltd., Tokyo, Japan

[**] Term: 14 Years

[21] Appl. No.: 612,813

[22] Filed: May 22, 1984

[30] Foreign Application Priority Data

Nov. 25, 1983 [JP] Japan 58-51154
[52] U.S. Cl. D14/100; D10/46
[58] Field of Search D10/46, 101, 103, 75, D10/78; D13/35, 4 C; D14/100, 107, 114; 324/72.5, 156, 114, 115

[56] References Cited
U.S. PATENT DOCUMENTS

D. 224,019 6/1972 Kalvitis D14/100
D. 248,232 6/1978 Stamper D14/100
D. 258,654 3/1981 Levy D14/100
D. 261,623 11/1981 Collister et al. D10/46

Primary Examiner—Louis S. Zarfes
Attorney, Agent, or Firm—Flynn, Thiel, Boutell & Tanis

[57] CLAIM

The ornamental design for a data processor for measuring instruments, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a data processor for measuring instruments showing our new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a rear elevational view thereof;
FIG. 4 is a top plan view thereof;
FIG. 5 is a bottom plan view thereof;
FIG. 6 is a left side elevational view thereof;
FIG. 7 is a right side elevational view thereof;
FIG. 8 is a sectional view taken on line 8—8 in FIG. 2; and
FIG. 9 is a sectional view taken on line 9—9 in FIG. 2.

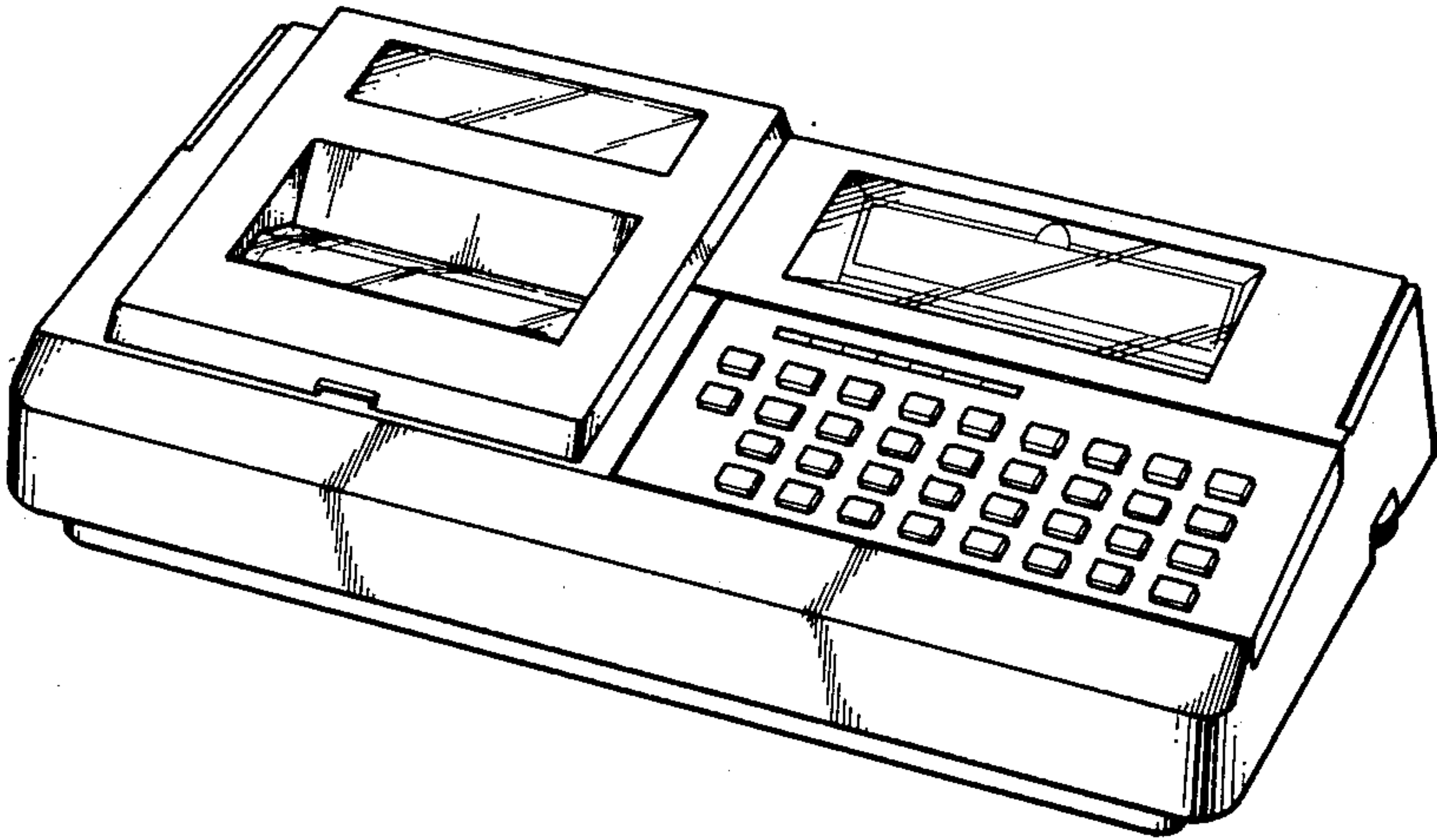


FIG. 1

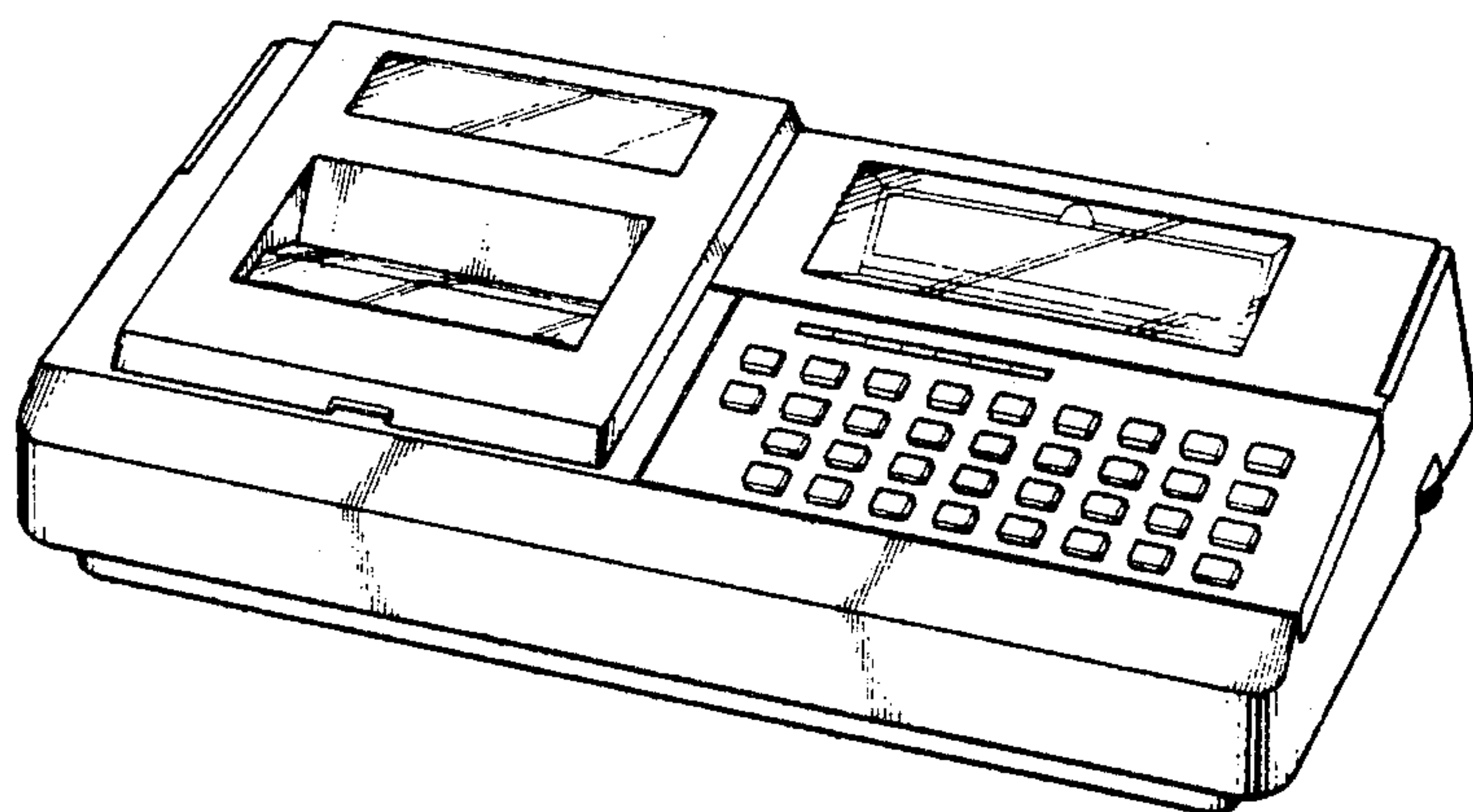


FIG. 2

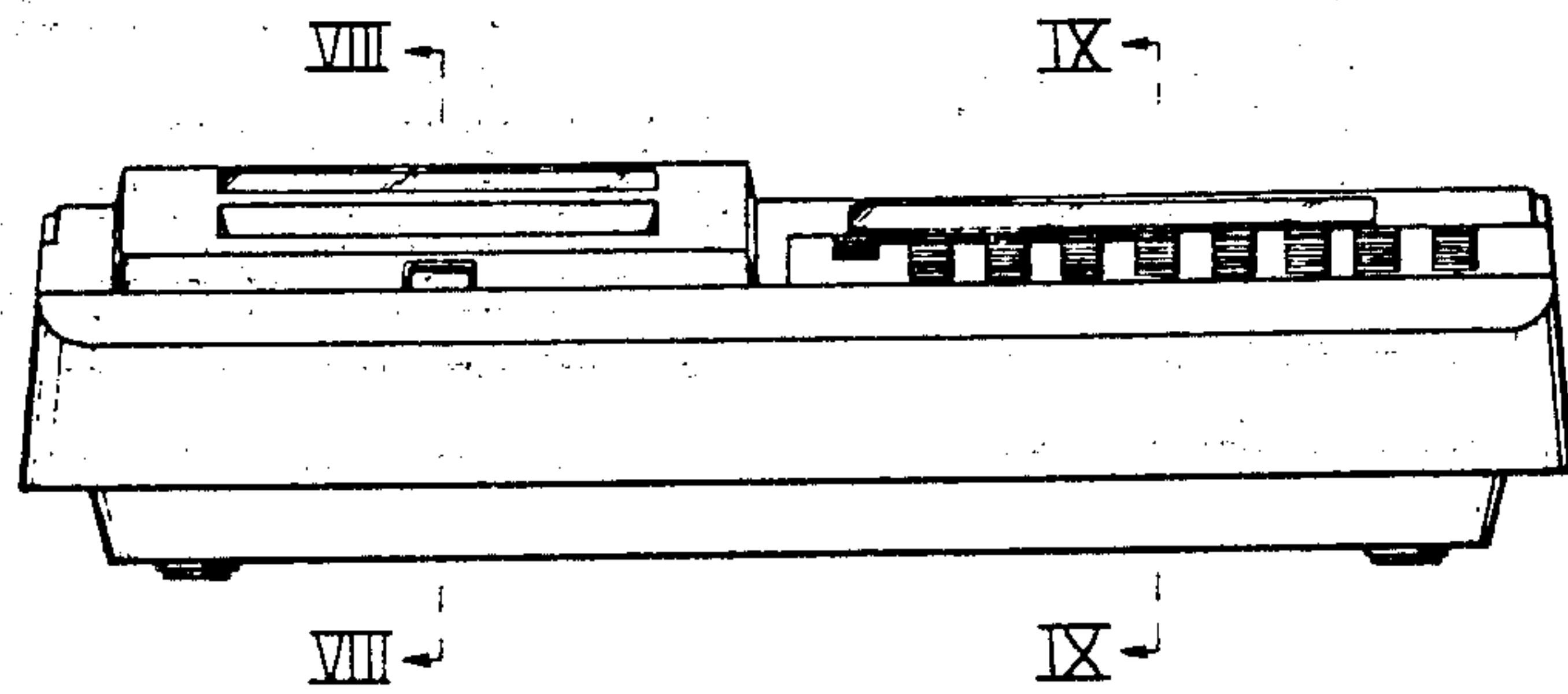


FIG. 3

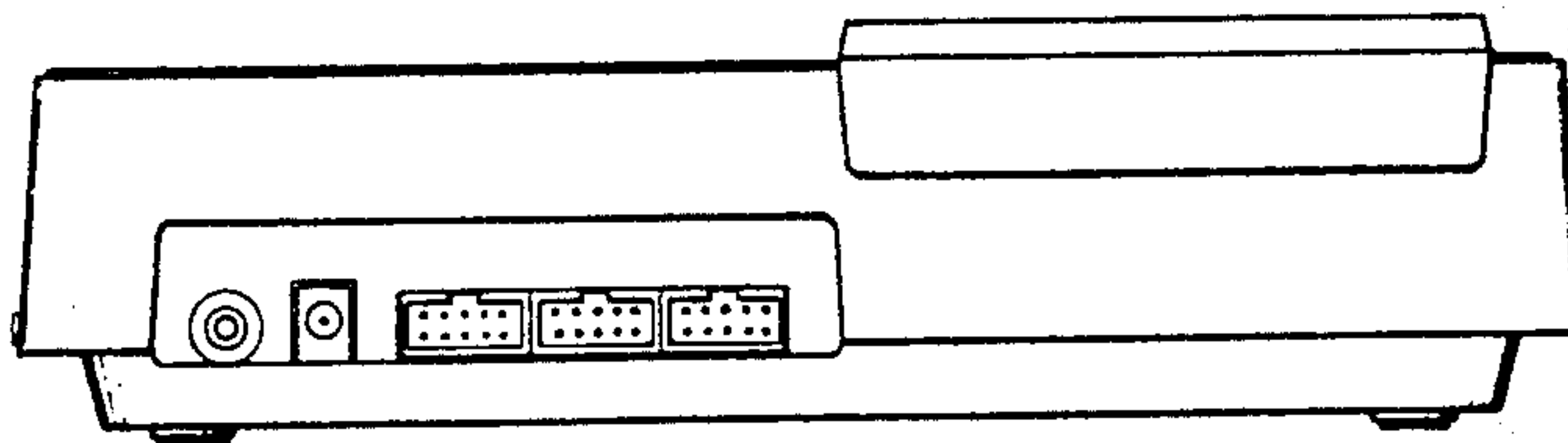


FIG. 4

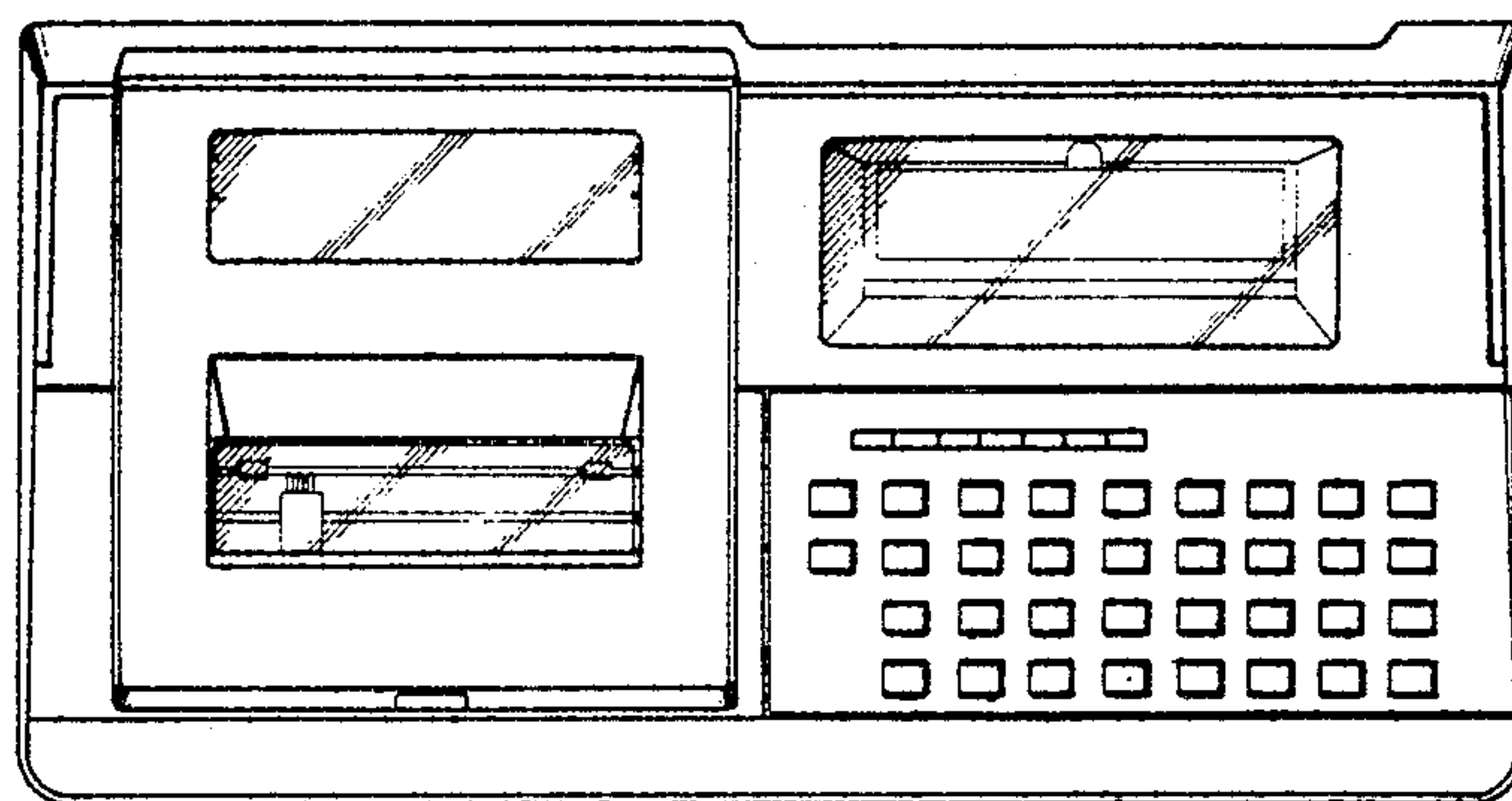


FIG. 5

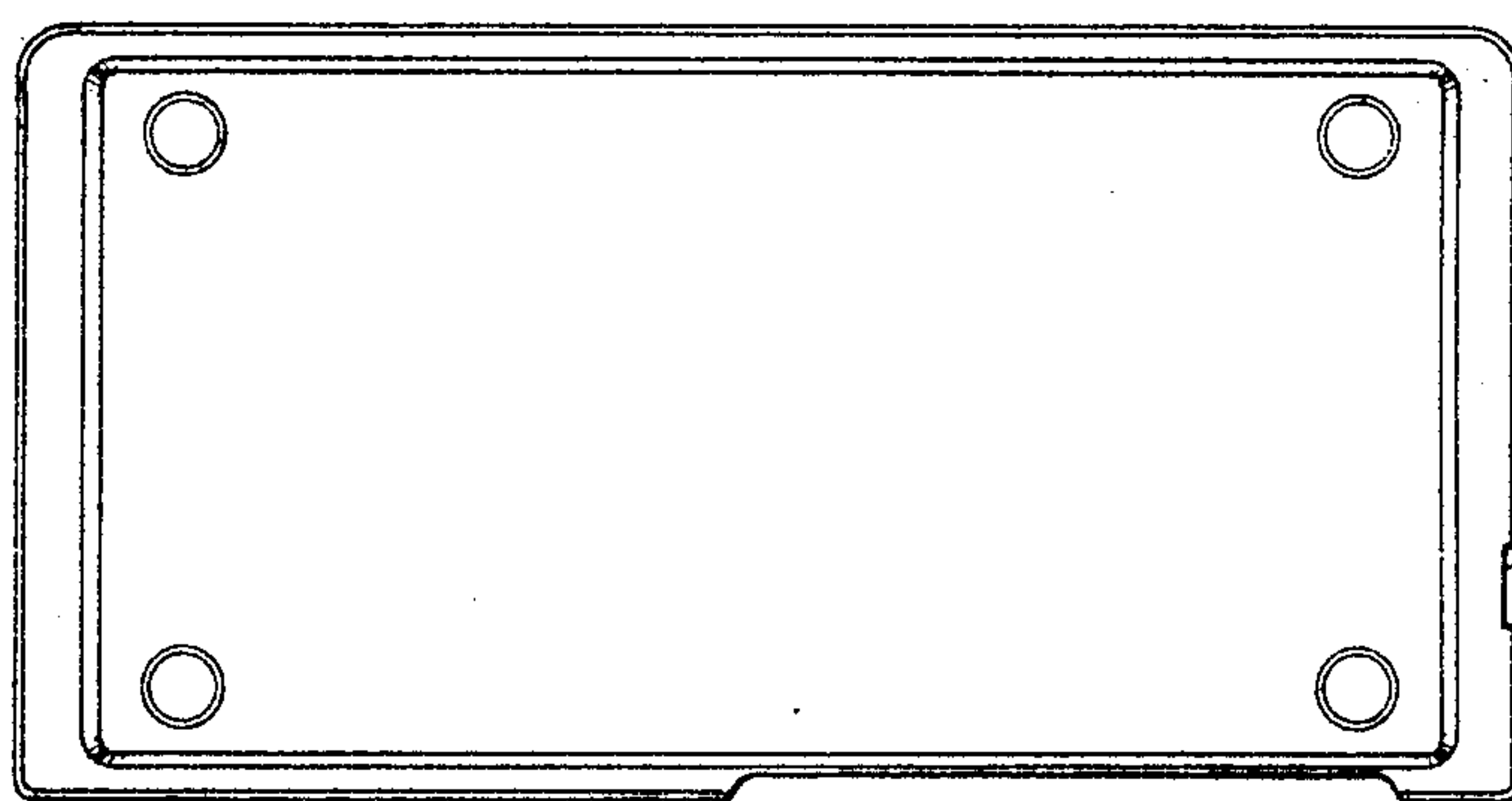


FIG. 6

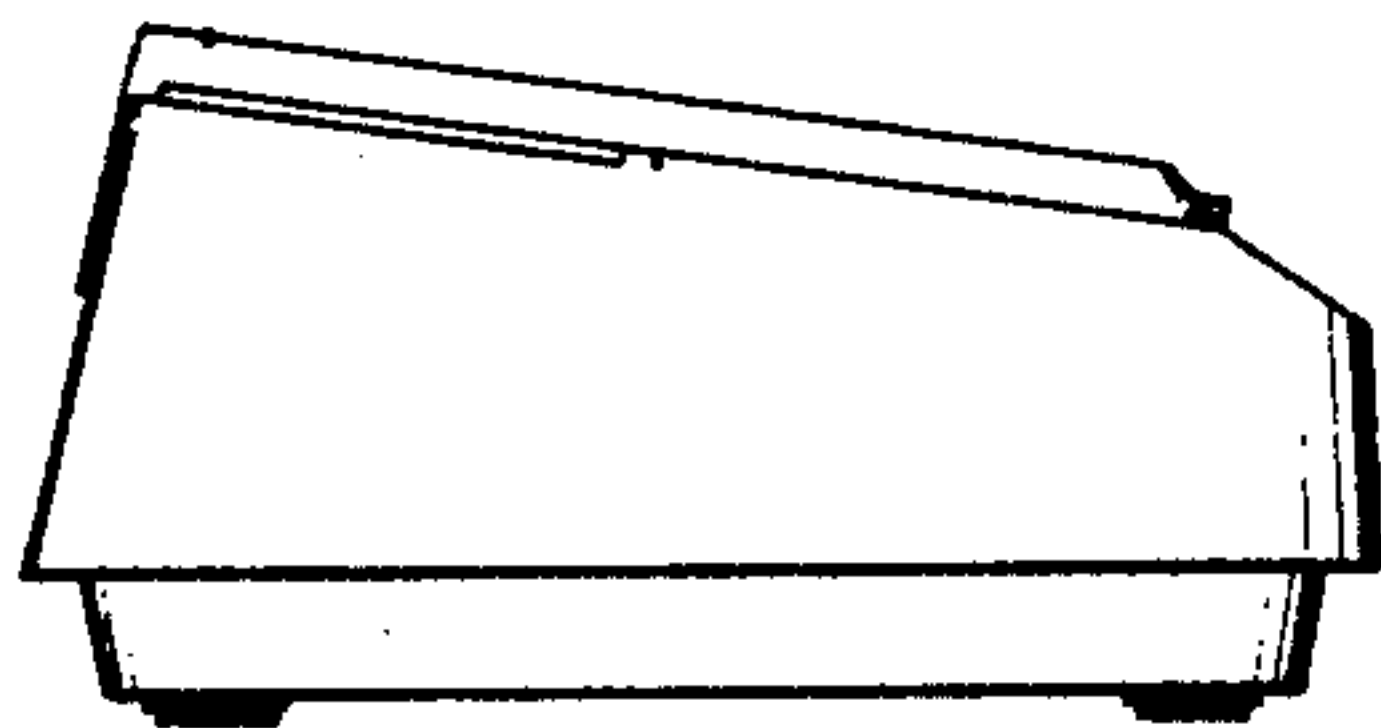


FIG. 7

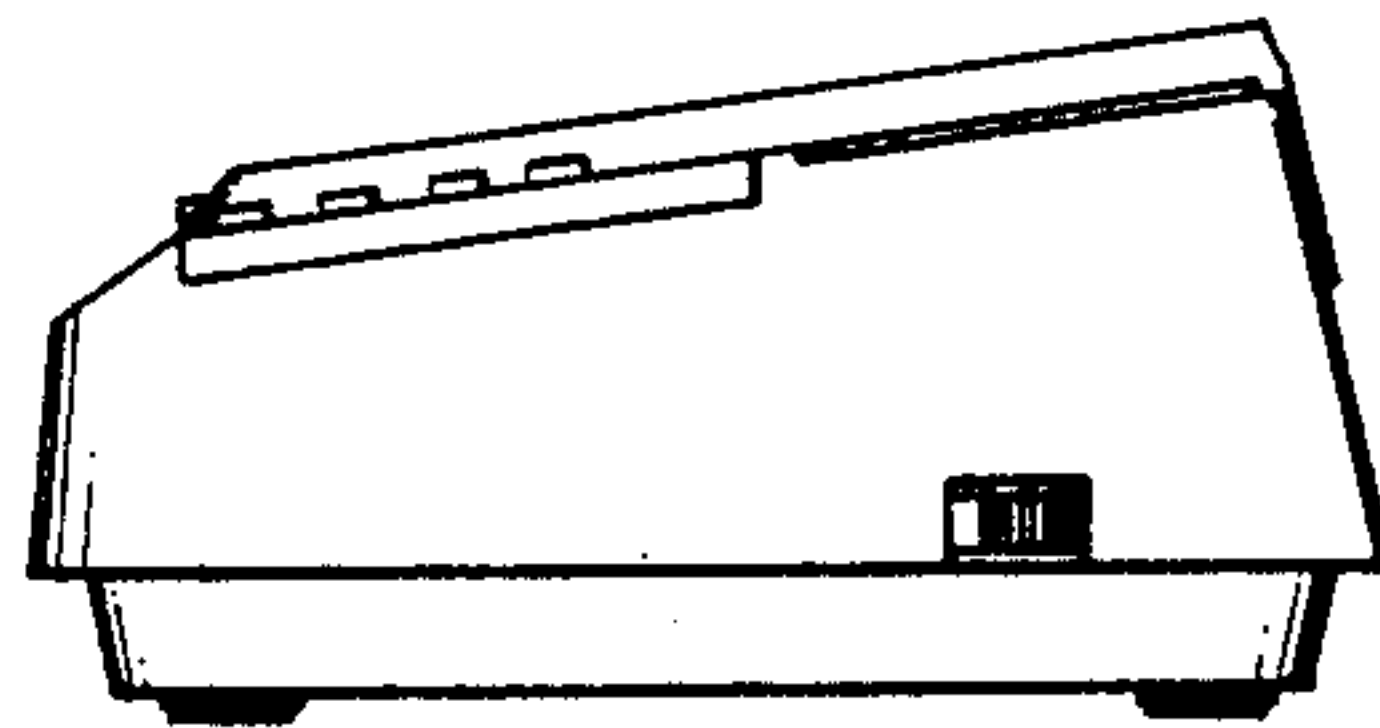


FIG. 8

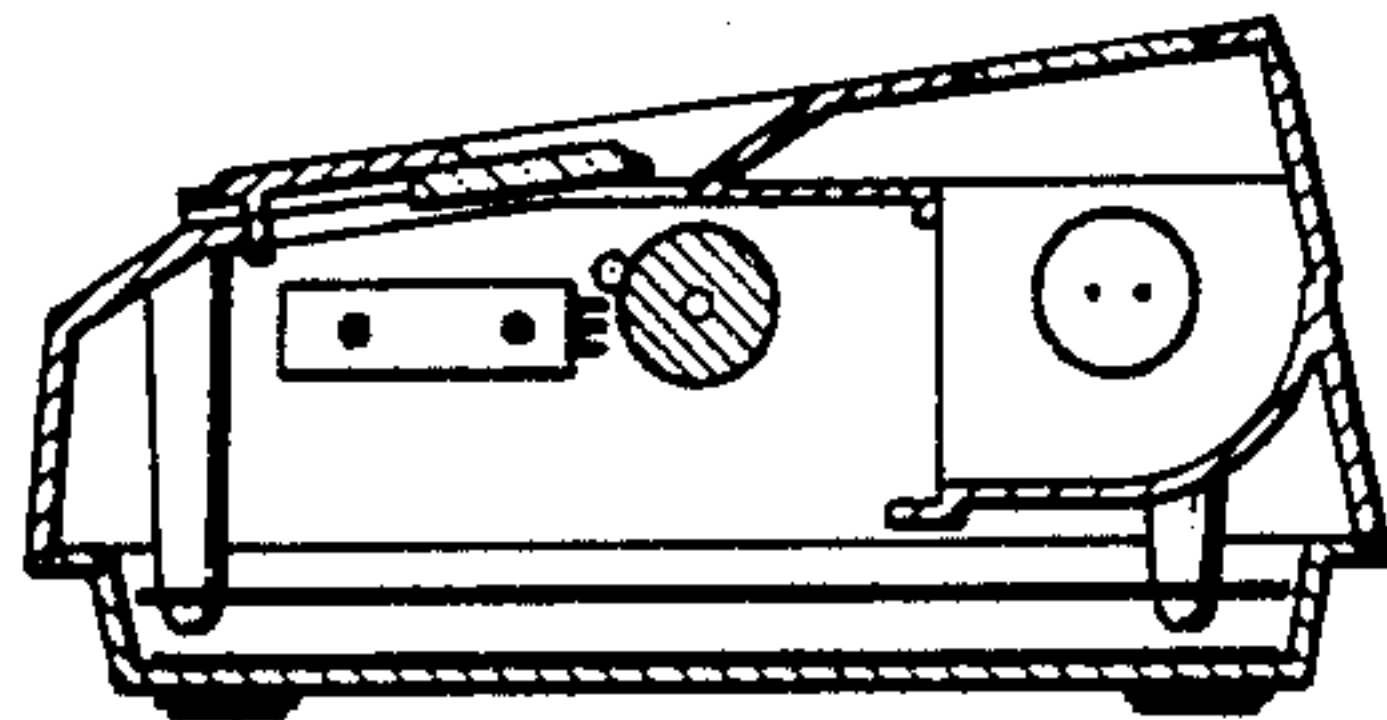


FIG. 9

